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May 2014

## **FDMS7602S**

# Dual N-Channel PowerTrench<sup>®</sup> MOSFET Q1: 30 V, 30 A, 7.5 m $\Omega$ Q2: 30 V, 30 A, 5.0 m $\Omega$

#### **Features**

Q1: N-Channel

- Max  $r_{DS(on)}$  = 7.5 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 12 A
- Max  $r_{DS(on)} = 12 \text{ m}\Omega$  at  $V_{GS} = 4.5 \text{ V}$ ,  $I_D = 10 \text{ A}$

Q2: N-Channel

- Max  $r_{DS(on)} = 5.0 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 17 \text{ A}$
- Max  $r_{DS(on)} = 6.8 \text{ m}\Omega$  at  $V_{GS} = 4.5 \text{ V}$ ,  $I_D = 14 \text{ A}$
- RoHS Compliant

#### **General Description**

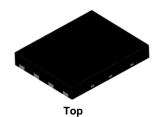
This device includes two specialized N-Channel MOSFETs in a dual MLP package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q1) and synchronous SyncFET<sup>TM</sup> (Q2) have been designed to provide optimal power efficiency.

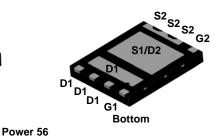
## **Applications**

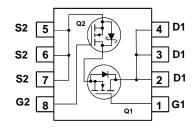
- Computing
- Communications
- General Purpose Point of Load



■ Notebook VCORE







## MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Parameter		Q1	Q2	Units
V <sub>DS</sub>	Drain to Source Voltage		30	30	V
$V_{GS}$	Gate to Source Voltage	(Note 3)	±20	±20	V
	Drain Current -Continuous	T <sub>C</sub> = 25 °C	30	30	
I <sub>D</sub>	-Continuous	T <sub>A</sub> = 25 °C	12 <sup>1a</sup>	17 <sup>1b</sup>	Α
	-Pulsed		40	60	
Б	Power Dissipation for Single Operation	T <sub>A</sub> = 25 °C	2.2 <sup>1a</sup>	2.5 <sup>1b</sup>	W
$P_{D}$	Power Dissipation for Single Operation	T <sub>A</sub> = 25 °C	1.0 <sup>1c</sup>	1.0 <sup>1d</sup>	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to	+150	°C

#### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	57 <sup>1a</sup>	50 <sup>1b</sup>	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	125 <sup>1c</sup>	120 <sup>1d</sup>	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	3.5	2	

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS7602S	FDMS7602S	Power 56	13 "	12 mm	3000 units

## **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted

Parameter	Test Conditions	Type	Min	Тур	Max	Units
cteristics						
Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$ $I_D = 1 mA, V_{GS} = 0 V$	Q1 Q2	30 30			V
Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C $I_D$ = 1 mA, referenced to 25 °C	Q1 Q2		15 15		mV/°C
Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V	Q1 Q2			1 500	μ <b>Α</b> μ <b>Α</b>
Gate to Source Leakage Current	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V	Q1 Q2			100 100	nA nA
	Cteristics  Drain to Source Breakdown Voltage  Breakdown Voltage Temperature Coefficient  Zero Gate Voltage Drain Current	Cteristics       Drain to Source Breakdown Voltage $I_D = 250 \mu A, V_{GS} = 0 \text{ V}$ $I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$ Breakdown Voltage Temperature $I_D = 250 \mu A, \text{ referenced to } 25 \text{ °C}$ Coefficient $I_D = 1 \text{ mA}, \text{ referenced to } 25 \text{ °C}$ Zero Gate Voltage Drain Current $V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$ Cote to Source Leakage Current $V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				

## **On Characteristics**

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$ $V_{GS} = V_{DS}, I_D = 1 mA$	Q1 Q2	1 1	1.8 1.8	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C $I_D$ = 1 mA, referenced to 25 °C	Q1 Q2		-6 -5		mV/°C
-	Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, \ I_D = 12 \text{ A}$ $V_{GS} = 4.5 \text{ V}, \ I_D = 10 \text{ A}$ $V_{GS} = 10 \text{ V}, \ I_D = 12 \text{ A}, \ T_J = 125 ^{\circ}\text{C}$	Q1		6.0 8.5 8.3	7.5 12 12	m0
r <sub>DS(on)</sub>	Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, \ I_D = 17 \text{ A}$ $V_{GS} = 4.5 \text{ V}, \ I_D = 14 \text{ A}$ $V_{GS} = 10 \text{ V}, \ I_D = 17 \text{ A}, \ T_J = 125 ^{\circ}\text{C}$	Q2		4.2 5.4 4.9	5.0 6.8 7.2	mΩ
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 12 \text{ A}$ $V_{DS} = 5 \text{ V}, I_{D} = 17 \text{ A}$	Q1 Q2		63 87		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	Q1: V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V, f = 1 MHZ	Q1 Q2	1315 2020	1750 2690	pF
C <sub>oss</sub>	Output Capacitance	Q2:	Q1 Q2	445 860	600 1145	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$	Q1 Q2	45 95	70 145	pF
R <sub>g</sub>	Gate Resistance		Q1 Q2	0.9 0.7		Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time			Q1 Q2	8.6 11	18 20	ns
t <sub>r</sub>	Rise Time	Q1:  V <sub>DD</sub> = 15 V, I <sub>D</sub> = 12 A,	, R <sub>GEN</sub> = 6 Ω	Q1 Q2	2.5 3.8	10 10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	Q2: V <sub>DD</sub> = 15 V, I <sub>D</sub> = 17 A,	P -60	Q1 Q2	20 27	32 43	ns
t <sub>f</sub>	Fall Time	V <sub>DD</sub> = 13 V, I <sub>D</sub> = 17 A,	, NGEN = 0 12	Q1 Q2	2.3 3.2	10 10	ns
$Q_g$	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V Q		Q1 Q2	20 33	28 46	nC
$Q_g$	Total Gate Charge	$V_{GS} = 0 V to 4.5 V I_D$	<sub>DD</sub> = 15 V, <sub>1</sub> = 12 A	Q1 Q2	9.3 16	13 22	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	Q: Vr	2 <sub>DD</sub> = 15 V,	Q1 Q2	4.3 5.8		nC
$Q_{gd}$	Gate to Drain "Miller" Charge	_	) = 17 A	Q1 Q2	2.2 4.6		nC

## **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
Drain-Sou	rce Diode Characteristics						
$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 12 \text{ A}$ (Note 2) $V_{GS} = 0 \text{ V}, I_S = 17 \text{ A}$ (Note 2)			0.8 0.8	1.2 1.2	V
t <sub>rr</sub>	Reverse Recovery Time	Q1 I <sub>F</sub> = 12 A, di/dt = 100 A/μs	Q1 Q2		27 29	43 46	ns
Q <sub>rr</sub>	Reverse Recovery Charge	Q2 $I_F = 17 \text{ A, di/dt} = 300 \text{ A/}\mu\text{s}$	Q1 Q2		10 31	18 50	nC

**Notes:**1:  $R_{\theta JA}$  is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



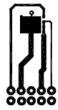
a. 57 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b. 50 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



c. 125 °C/W when mounted on a minimum pad of 2 oz copper



d. 120 °C/W when mounted on a minimum pad of 2 oz copper

- 2: Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%.
- 3: As an N-ch device, the negative Vgs rating is for low duty cycle pulse ocurrence only. No continuous rating is implied.

## Typical Characteristics (Q1 N-Channel)T<sub>J</sub> = 25°C unless otherwise noted

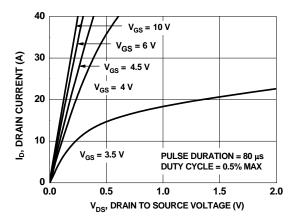


Figure 1. On Region Characteristics

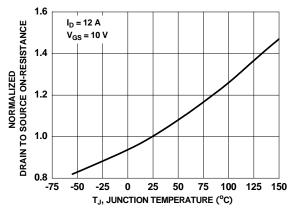


Figure 3. Normalized On Resistance vs Junction Temperature

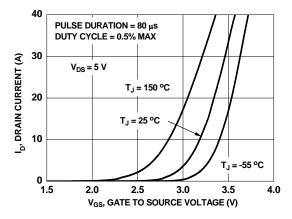


Figure 5. Transfer Characteristics

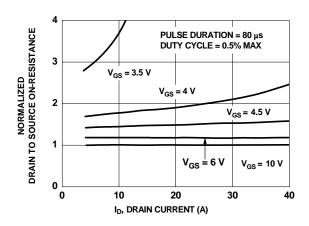


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

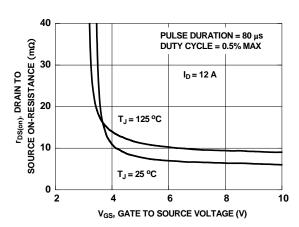


Figure 4. On-Resistance vs Gate to Source Voltage

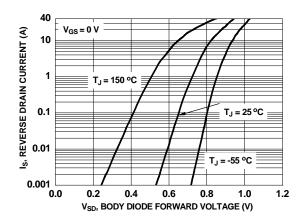


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

## Typical Characteristics (Q1 N-Channel)T<sub>J</sub> = 25°C unless otherwise noted

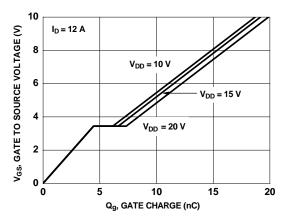


Figure 7. Gate Charge Characteristics

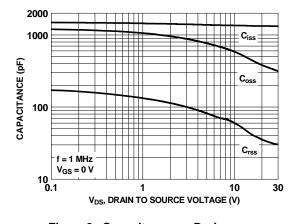


Figure 8. Capacitance vs Drain to Source Voltage

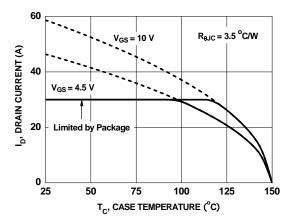


Figure 9. Maximum Continuous Drain Current vs Case Temperature

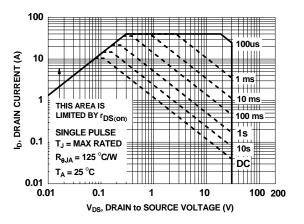


Figure 10. Forward Bias Safe Operating Area

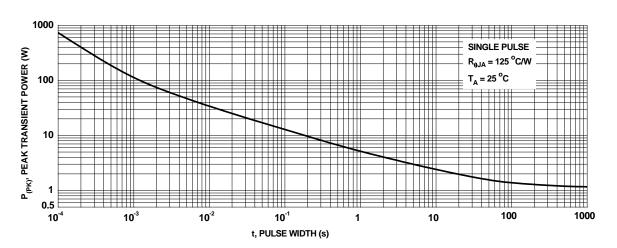


Figure 11. Single Pulse Maximum Power Dissipation

## Typical Characteristics (Q1 N-Channel)T<sub>J</sub> = 25°C unless otherwise noted

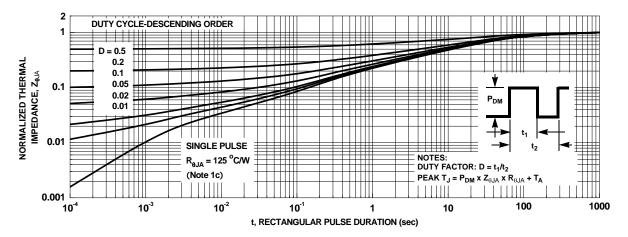


Figure 12. Junction-to-Ambient Transient Thermal Response Curve

## **Typical Characteristics (Q2 SyncFET)**

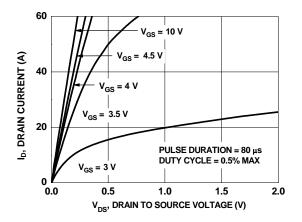


Figure 13. On-Region Characteristics

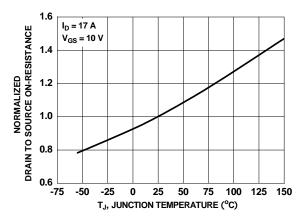


Figure 15. Normalized On-Resistance vs Junction Temperature

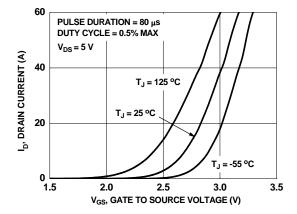


Figure 17. Transfer Characteristics

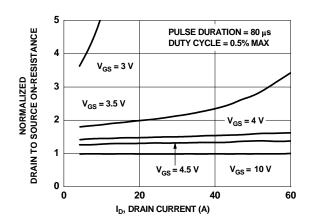


Figure 14. Normalized on-Resistance vs Drain Current and Gate Voltage

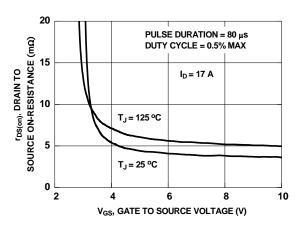


Figure 16. On-Resistance vs Gate to Source Voltage

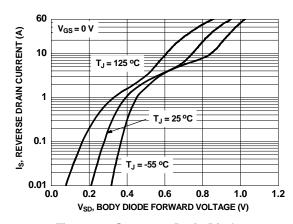


Figure 18. Source to Drain Diode Forward Voltage vs Source Current

## **Typical Characteristics (Q2 SyncFET)**

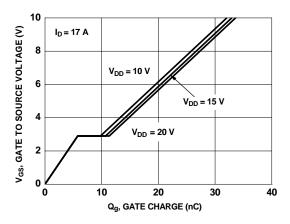


Figure 19. Gate Charge Characteristics

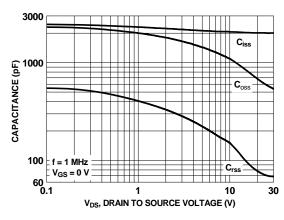


Figure 20. Capacitance vs Drain to Source Voltage

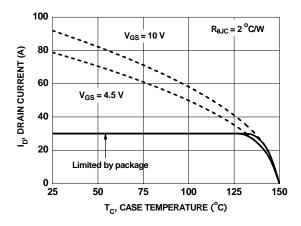


Figure 21. Maximum Continuous Drain Current vs Case Temperature

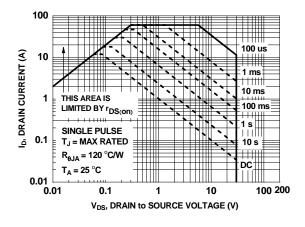


Figure 22. Forward Bias Safe Operating Area

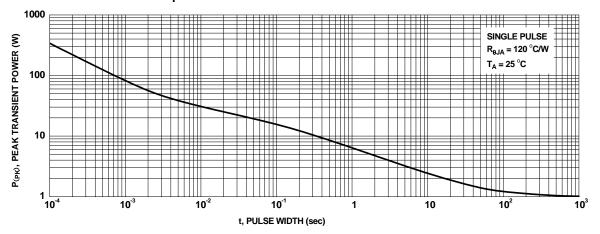


Figure 23. Single Pulse Maximum Power Dissipation

## **Typical Characteristics (Q2 SyncFET)**

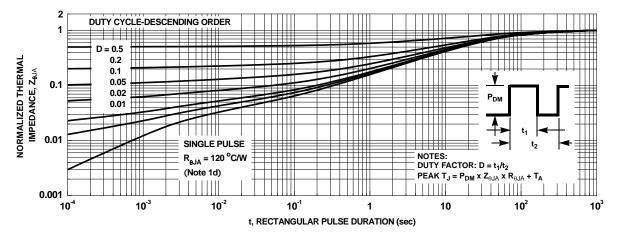


Figure 24. Junction-to-Ambient Transient Thermal Response Curve

## Typical Characteristics (continued)

# SyncFET<sup>TM</sup> Schottky body diode Characteristics

Fairchild's SyncFET<sup>TM</sup> process embeds a Schottky diode in parallel with PowerTrench<sup>®</sup> MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 25 shows the reverse recovery characteristic of the FDMS7602S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

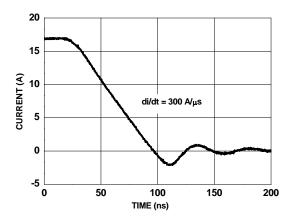


Figure 25. FDMS7602S SyncFET<sup>TM</sup> Body Diode Reverse Recovery Characteristic

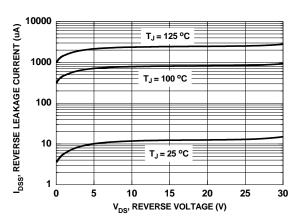
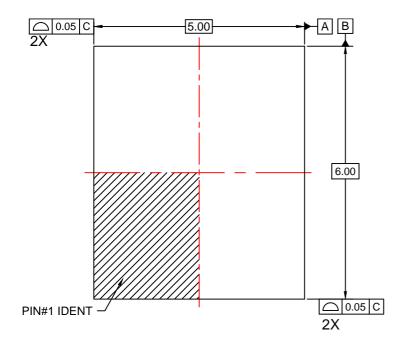
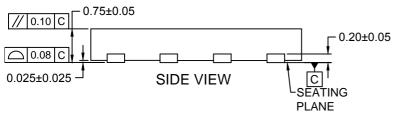
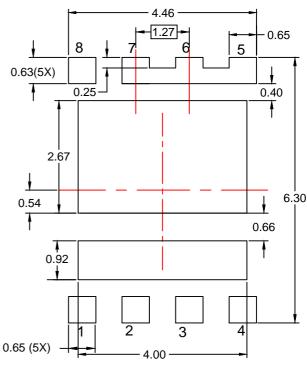


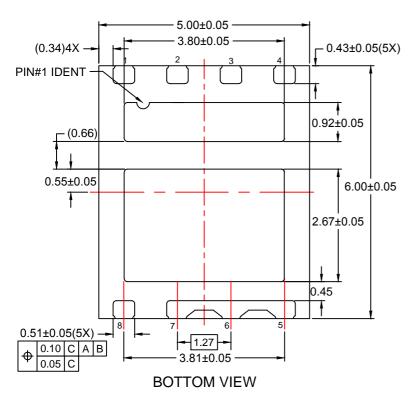
Figure 26. SyncFET<sup>TM</sup> Body Diode Reverse Leakage vs. Drain-Source Voltage





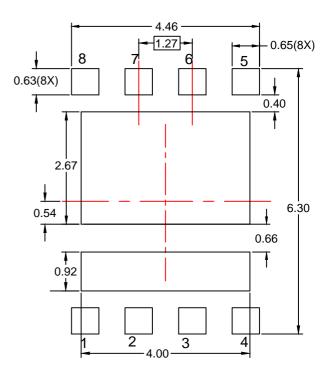


RECOMMENDED LAND PATTERN (OPTION 1 - FUSED LEADS 5,6,7)



## NOTES:

- A. PACKAGE DOES NOT FULLY CONFORM TO JEDEC STANDARD.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN.
- E. DRAWING FILENAME: MKT-MLP08Prev2.



RECOMMENDED LAND PATTERN (OPTION 2 - ISOLATED LEADS)



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